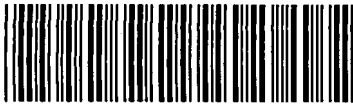


Search Notes

Application/Control No.

10/708,536

Examiner

Erin D. Chiem

Applicant(s)/Patent under
Reexamination

ZHOU ET AL.

Art Unit

2883

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
text search		edc
(multi multiple plurality) near2 (film layer) same grin	6/11/2007	EDC